



FORM: PTO-1449 (REV: 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Atty Docket No: 94-0302.02	Serial No: 09/654,093
INFORMATION DISCLOSURE STATEMENT BY APPLICANT  (37 CFR 1.98(b)) (use several sheets if necessary)		Applicant: Thakur et al.	
		Filing Date: 8/31/00	Group:

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass
PEBA	AA 6,033,979	03/07/00	Endo	438	622
PEBA	AC 5,585,308	12/17/96	Sardella	437	190
PEBA	AD 5,552,343	09/03/96	Hsu	437	195
PEBA	AE 5,531,183	07/02/96	Sivaramakrishnam et al.	117	093
PEBA	AF 5,474,955	12/12/95	Thakur	437	173
PEBA	AG 5,399,532	03/21/95	Lee et al.	437	228
PEBA	AH 5,384,288	01/24/95	Ying	437	228
PEBA	AI 5,372,974	12/13/94	Doan et al.	437	240
PEBA	AJ 5,260,232	11/09/93	Muroyama et al.	437	187
PEBA	AK 5,236,862	08/17/93	Pfiester et al.	437	070
PEBA	AL 5,196,907	03/23/93	Birkle et al.	257	289
PEBA	AM 5,166,088	11/24/92	Ueda et al.	437	047
PEBA	AN 5,164,330	11/17/92	Davis et al.	437	192
PEBA	AO 5,077,238	12/31/91	Fujii et al.	437	228
PEBA	AP 4,992,840	02/12/91	Haddad et al.	357	23.15
PEBA	AQ 4,917,759	04/17/90	Fisher et al.	156	643
PEBA	AR 4,879,257	11/07/89	Patrick	437	195
PEBA	AS 4,849,797	07/18/89	Ukai et al.	357	237
PEBA	AT 4,824,802	04/25/89	Brown et al.	437	192
PEBA	AU 4,708,767	11/24/87	Bril	437	018
PEBA	AV 3,925,572	12/09/75	Naber	427	087

## FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AX 04-326732	11/16/92	Japan	H01L-021	316	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	AY 04-067632	03/03/92	Japan	H01L-021	3205	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	AZ 03-280543	12/11/91	Japan	H01L-021	3205	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	BA 01-047055	02/21/89	Japan	H01L-021	90	<input type="checkbox"/>	<input checked="" type="checkbox"/>

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OTHER ART (including author, title, date, pertinent pages, etc.)

	BB	S. Wolf, "Silicon Processing for the VLSI Era", Vol. II, pp. 45, 51, 194-99, 370, 382, 387-88, June, 1990
	BC	Butler, John, Greg Allen, Anthony Hall, and Romuald Nowak, "Electrical Characterization of Doped and Undoped PECVD TEOS Oxides", presented at VMIC, June 1990.

Examiner: <i>Paul E Brooke</i>	Date Considered: <i>1/18/2001</i>
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